

## 4-1/2 Digit Analog-To-Digital Converter

### FEATURES

- Low Roll-Over Error .....  $\pm 1$  Count Max
- Guaranteed Nonlinearity Error .....  $\pm 1$  Count Max
- Guaranteed Zero Reading for 0V Input
- True Polarity Indication at Zero for Null Detection
- Multiplexed BCD Data Output
- TTL-Compatible Outputs
- Differential Input
- Control Signals Permit Interface to UARTs and  $\mu$ Processors
- Auto-Ranging Supported With Overrange and Underrange Signals
- Blinking Display Visually Indicates Overrange Condition
- Low Input Current ..... 1pA
- Low Zero Reading Drift .....  $2\mu\text{V}/^\circ\text{C}$
- Available in DIP and Surface-Mount Packages

### GENERAL DESCRIPTION

The TC7135 4-1/2 digit analog-to-digital converter (ADC) offers 50 ppm (1 part in 20,000) resolution with a maximum nonlinearity error of 1 count. An auto-zero cycle reduces zero error to below  $10\mu\text{V}$  and zero drift to  $0.5\mu\text{V}/^\circ\text{C}$ . Source impedance errors are minimized by a  $10\text{pA}$  maximum input current. Roll-over error is limited to  $\pm 1$  count.

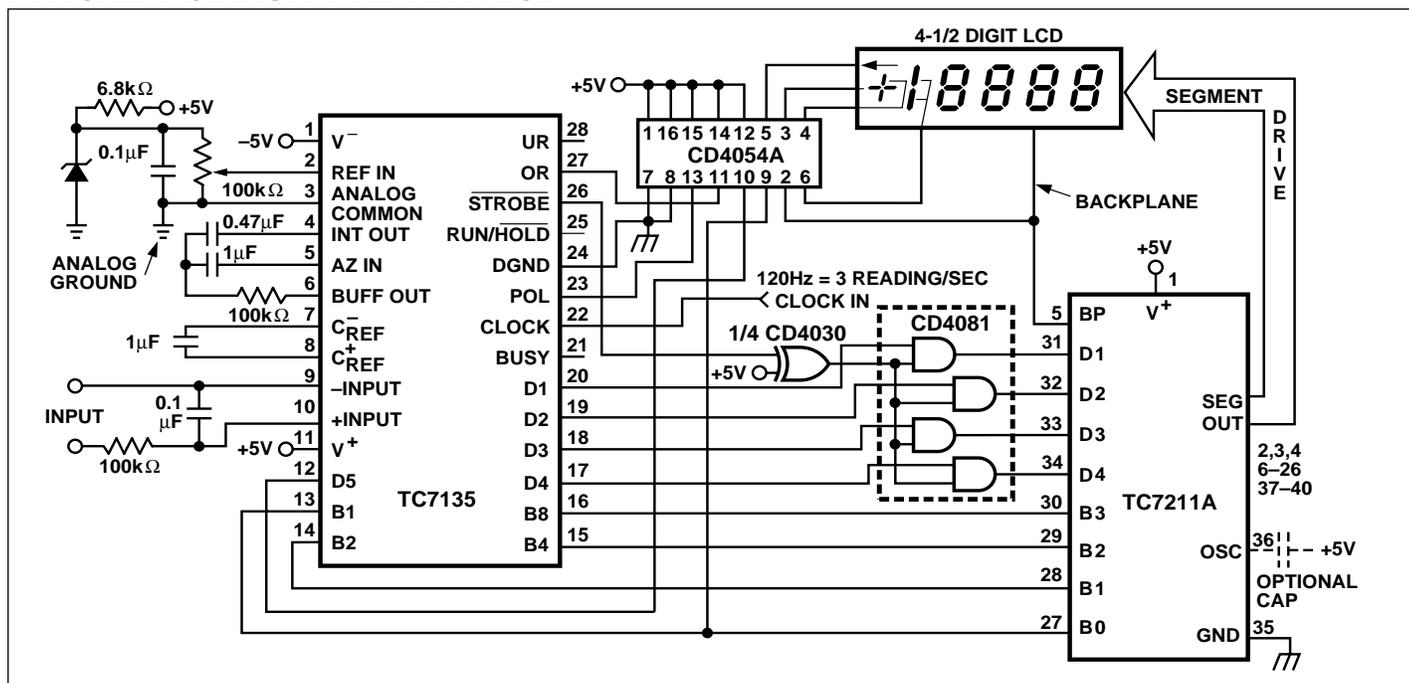
By combining the TC7135 with a TC7211A (LCD) driver, a 4-1/2 digit display DVM or DPM can be constructed. Overrange and underrange signals support automatic range switching and special display blanking/flashing applications.

Microprocessor-based measurement systems are supported by BUSY, STROBE, and RUN/HOLD control signals. Remote data acquisition systems with data transfer via UARTs are also possible. The additional control pins and multiplexed BCD outputs make the TC7135 the ideal converter for display or microprocessor-based measurement systems.

### ORDERING INFORMATION

Part No.	Package	Temperature Range
TC7135CBU	64-Pin PQFP	$0^\circ\text{C}$ to $+70^\circ\text{C}$
TC7135CLI	28-Pin PLCC	$0^\circ\text{C}$ to $+70^\circ\text{C}$
TC7135CPI	28-Pin PDIP	$0^\circ\text{C}$ to $+70^\circ\text{C}$

### TYPICAL 4-1/2 DIGIT DVM WITH LCD



# 4-1/2 Digit Analog-To-Digital Converter

## TC7135

### ABSOLUTE MAXIMUM RATINGS\* (Note 1)

Positive Supply Voltage	+6V
Negative Supply Voltage	-9V
Analog Input Voltage (Pin 9 or 10)	V <sup>+</sup> to V <sup>-</sup> (Note 2)
Reference Input Voltage (Pin 2)	V <sup>+</sup> to V <sup>-</sup>
Clock Input Voltage	0V to V <sup>+</sup>
Operating Temperature Range	0°C to +70°C
Storage Temperature Range	-65°C to +160°C
Lead Temperature (Soldering, 10 sec)	+300°C

### Package Power Dissipation (T<sub>A</sub> ≤ 70°C)

PDIP	1.14W
PLCC	1.00W
PQFP	1.14W

\*Static-sensitive device. Unused devices must be stored in conductive material to protect them from static discharge and static fields. Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions above those indicated in the operational sections of the specifications is not implied.

### ELECTRICAL CHARACTERISTICS: T<sub>A</sub> = +25°C, f<sub>CLK</sub> = 120kHz, V<sup>+</sup> = +5V, V<sup>-</sup> = -5V (Figure 1)

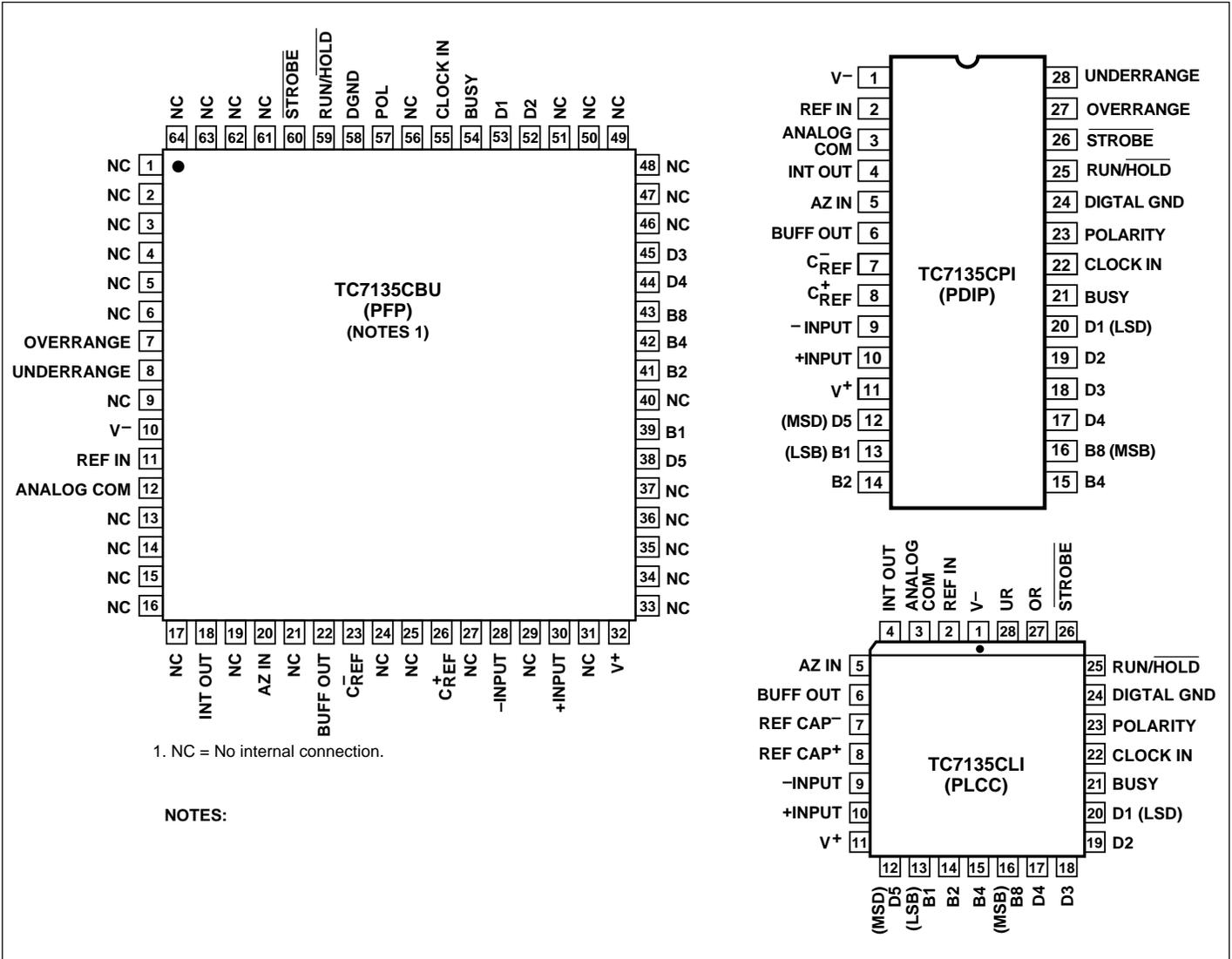
Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
<b>Analog</b>						
	Display Reading With Zero Volt Input	Notes 2 and 3	-0.0000	±0.0000	+0.0000	Display Reading
TC <sub>Z</sub>	Zero Reading Temperature Coefficient	V <sub>IN</sub> = 0V Note 4	—	0.5	2	μV/°C
TC <sub>FS</sub>	Full-Scale Temperature Coefficient	V <sub>IN</sub> = 2V Notes 4 and 5	—	—	5	ppm/°C
NL	Nonlinearity Error	Note 6	—	0.5	1	Count
DNL	Differential Linearity Error	Note 6	—	0.01	—	LSB
	Display Reading in Ratiometric Operation	V <sub>IN</sub> = V <sub>REF</sub> Note 2	+0.9996	+0.9999	+1.0000	Display Reading
±FSE	± Full-Scale Symmetry Error (Roll-Over Error)	-V <sub>IN</sub> = +V <sub>IN</sub> Note 7	—	0.5	1	Count
I <sub>IN</sub>	Input Leakage Current	Note 3	—	1	10	pA
V <sub>N</sub>	Noise	Peak-to-Peak Value Not Exceeded 95% of Time	—	15	—	μV <sub>P-P</sub>
<b>Digital</b>						
I <sub>IL</sub>	Input Low Current	V <sub>IN</sub> = 0V	—	10	100	μA
I <sub>IH</sub>	Input High Current	V <sub>IN</sub> = +5V	—	0.08	10	μA
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 1.6mA	—	0.2	0.4	V
V <sub>OH</sub>	Output High Voltage					
	B <sub>1</sub> , B <sub>2</sub> , B <sub>4</sub> , B <sub>8</sub> , D <sub>1</sub> -D <sub>5</sub>	I <sub>OH</sub> = 1mA	2.4	4.4	5	V
	Busy, Polarity, Overrange, Underrange, Strobe	I <sub>OH</sub> = 10μA	4.9	4.99	5	V
f <sub>CLK</sub>	Clock Frequency	Note 8	0	120	1200	kHz
<b>Power Supply</b>						
V <sup>+</sup>	Positive Supply Voltage		4	5	6	V
V <sup>-</sup>	Negative Supply Voltage		-3	-5	-8	V
I <sup>+</sup>	Positive Supply Current	f <sub>CLK</sub> = 0Hz	—	1	3	mA
I <sup>-</sup>	Negative Supply Current	f <sub>CLK</sub> = 0Hz	—	0.7	3	mA
PD	Power Dissipation	f <sub>CLK</sub> = 0Hz	—	8.5	30	mW

- NOTES:**
- Limit input current to under 100μA if input voltages exceed supply voltage.
  - Full-scale voltage = 2V.
  - V<sub>IN</sub> = 0V.
  - 0°C ≤ T<sub>A</sub> ≤ +70°C.
  - External reference temperature coefficient less than 0.01 ppm/°C.
  - 2V ≤ V<sub>IN</sub> ≤ +2V. Error of reading from best fit straight line.
  - |V<sub>IN</sub>| = 1.9959.
  - Specification related to clock frequency range over which the TC7135 correctly performs its various functions. Increased errors result at higher operating frequencies.

# 4-1/2 Digit Analog-To-Digital Converter

TC7135

## PIN CONFIGURATIONS



# 4-1/2 Digit Analog-To-Digital Converter

## TC7135

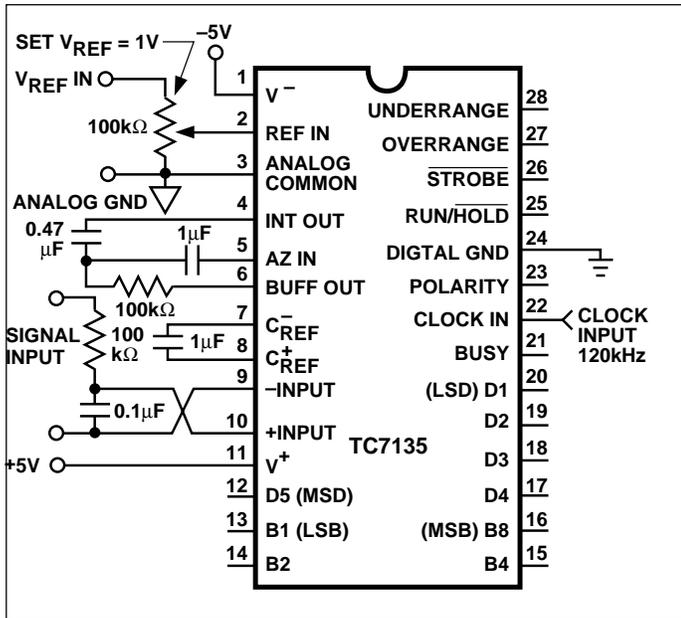


Figure 1. Test Circuit

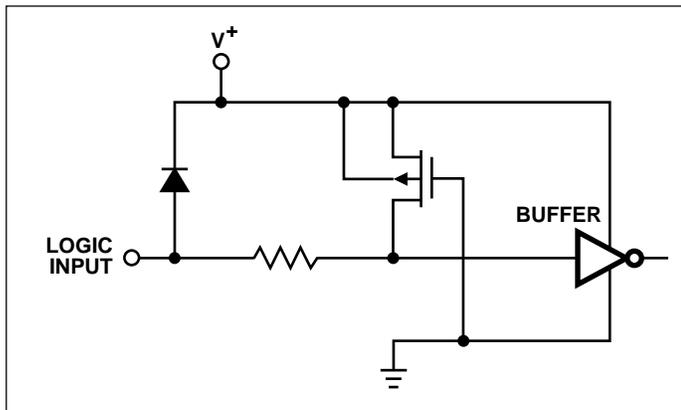


Figure 2. Digital Logic Input

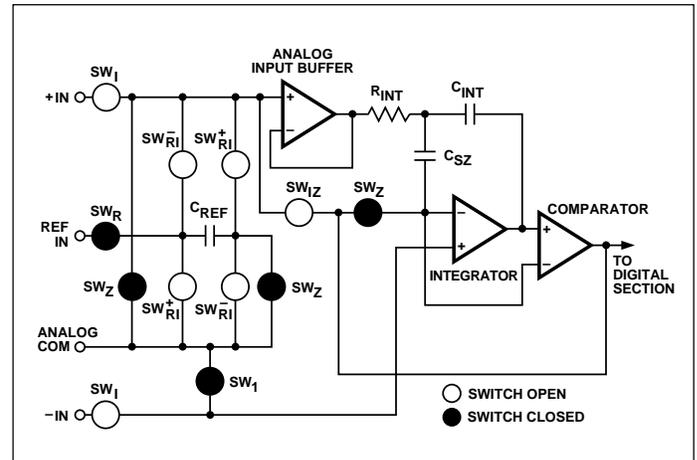


Figure 3B. System Zero Phase

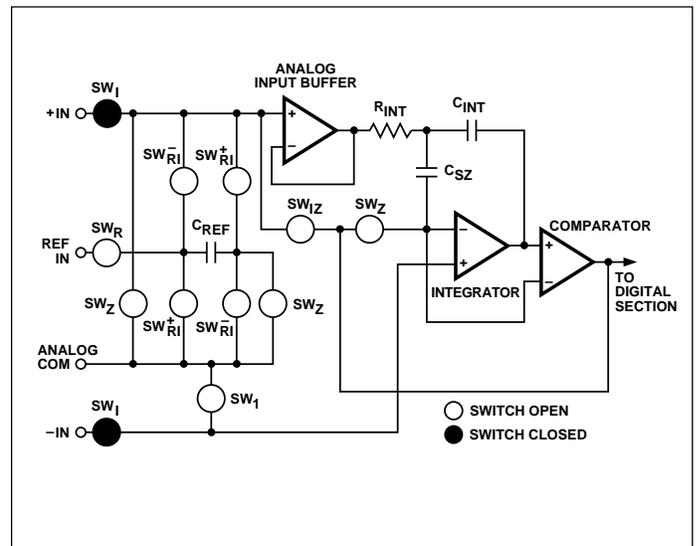


Figure 3C. Input Signal Integration Phase

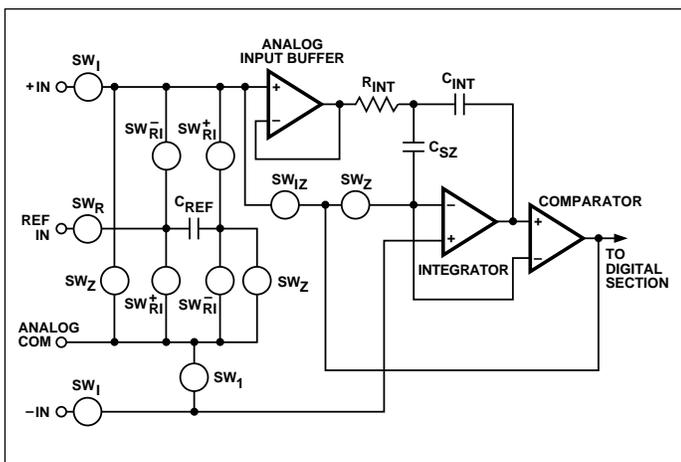


Figure 3A. Internal Analog Switches

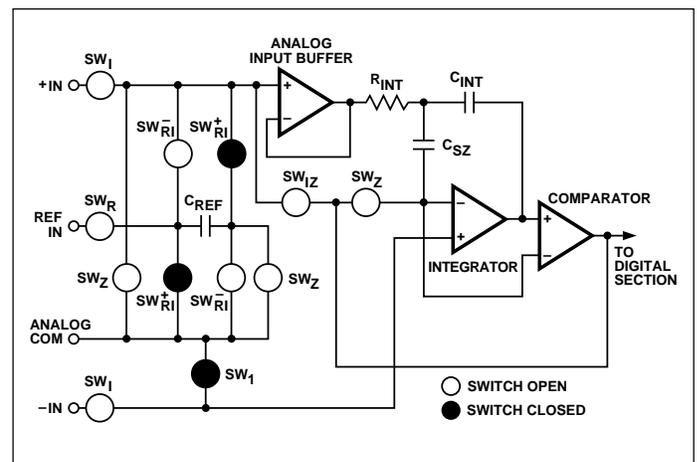


Figure 3D. Reference Voltage Integration Phase

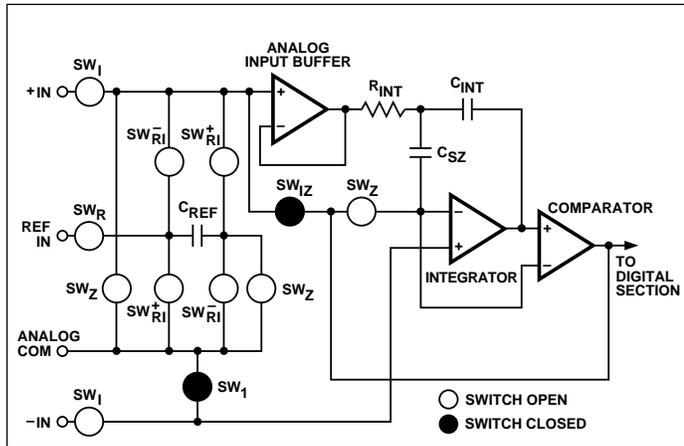


Figure 3E. Integrator Output Zero Phase

## GENERAL THEORY OF OPERATION

(All Pin Designations Refer to 28-Pin DIP)

### Dual-Slope Conversion Principles

The TC7135 is a dual-slope, integrating analog-to-digital converter. An understanding of the dual-slope conversion technique will aid in following detailed TC7135 operational theory.

The conventional dual-slope converter measurement cycle has two distinct phases:

- (1) Input signal integration
- (2) Reference voltage integration (deintegration)

The input signal being converted is integrated for a fixed time period, measured by counting clock pulses. An opposite polarity constant reference voltage is then integrated until the integrator output voltage returns to zero. The reference integration time is directly proportional to the input signal.

In a simple dual-slope converter, a complete conversion requires the integrator output to "ramp-up" and "ramp-down."

A simple mathematical equation relates the input signal, reference voltage, and integration time:

$$\frac{1}{RC} \int_0^{t_{SI}} V_{IN}(t) dt = \frac{V_R t_{RI}}{RC}$$

where:

- $V_R$  = Reference voltage
- $t_{SI}$  = Signal integration time (fixed)
- $t_{RI}$  = Reference voltage integration time (variable).

For a constant  $V_{IN}$ :

$$V_{IN} = V_R \left[ \frac{t_{RI}}{t_{SI}} \right]$$

The dual-slope converter accuracy is unrelated to the integrating resistor and capacitor values, as long as they are stable during a measurement cycle. Noise immunity is an inherent benefit. Noise spikes are integrated, or averaged, to zero during integration periods. Integrating ADCs are immune to the large conversion errors that plague successive approximation converters in high-noise environments. (See Figure 4.)

### TC7135 Operational Theory

The TC7135 incorporates a system zero phase and integrator output voltage zero phase to the normal two-phase dual-slope measurement cycle. Reduced system errors, fewer calibration steps, and a shorter overrange recovery time result.

The TC7135 measurement cycle contains four phases:

- (1) System zero
- (2) Analog input signal integration
- (3) Reference voltage integration
- (4) Integrator output zero

Internal analog gate status for each phase is shown in Table 1.

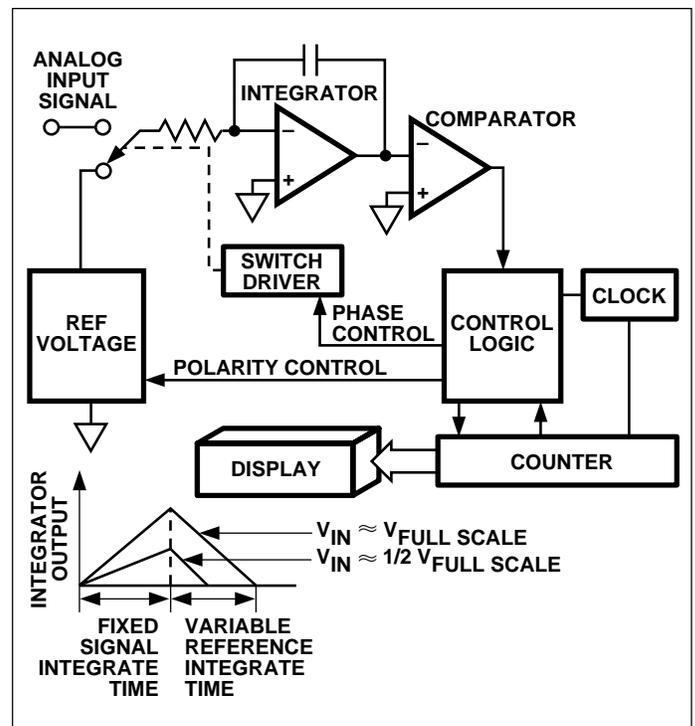


Figure 4. Basic Dual-Slope Converter

## TC7135

**Table 1. Internal Analog Gate Status**

Conversion Cycle Phase	Internal Analog Gate Status						Reference Schematic	
	SW <sub>I</sub>	SW <sub>RI</sub> <sup>+</sup>	SW <sub>RI</sub> <sup>-</sup>	SW <sub>Z</sub>	SW <sub>R</sub>	SW <sub>I</sub>		SW <sub>Iz</sub>
System Zero				Closed	Closed	Closed	3B	
Input Signal Integration	Closed						3C	
Reference Voltage Integration		Closed*				Closed	3D	
Integrator Output Zero						Closed	Closed	3E

\*NOTE: Assumes a positive polarity input signal. SW<sub>RI</sub><sup>-</sup> would be closed for a negative input signal.

### System Zero Phase

During this phase, errors due to buffer, integrator, and comparator offset voltages are compensated for by charging C<sub>AZ</sub> (auto-zero capacitor) with a compensating error voltage. With zero input voltage, the integrator output remains at zero.

The external input signal is disconnected from the internal circuitry by opening the two SW<sub>I</sub> switches. The internal input points connect to analog common. The reference capacitor charges to the reference voltage potential through SW<sub>R</sub>. A feedback loop, closed around the integrator and comparator, charges the C<sub>AZ</sub> with a voltage to compensate for buffer amplifier, integrator, and comparator offset voltages. (See Figure 3B.)

### Analog Input Signal Integration Phase

The TC7135 integrates the differential voltage between the +INPUT and -INPUT. The differential voltage must be within the device's common-mode range; -1V from either supply rail, typically.

The input signal polarity is determined at the end of this phase. (See Figure 3C.)

### Reference Voltage Integration Phase

The previously-charged reference capacitor is connected with the proper polarity to ramp the integrator output back to zero. (See Figure 3D.) The digital reading displayed is:

$$\text{Reading} = 10,000 \left[ \frac{\text{Differential Input}}{V_{\text{REF}}} \right]$$

### Integrator Output Zero Phase

This phase guarantees the integrator output is at 0V when the system zero phase is entered and that the true system offset voltages are compensated for. This phase normally lasts 100 to 200 clock cycles. If an overrange condition exists, the phase is extended to 6200 clock cycles. (See Figure 3E.)

## Analog Section Functional Description

### Differential Inputs

The TC7135 operates with differential voltages (+INPUT, pin 10 and -INPUT, pin 9) within the input amplifier common-mode range which extends from 1V below the positive supply to 1V above the negative supply. Within this common-mode voltage range, an 86dB common-mode rejection ratio is typical.

The integrator output also follows the common-mode voltage and must not be allowed to saturate. A worst-case condition exists, for example, when a large positive common-mode voltage with a near full-scale negative differential input voltage is applied. The negative input signal drives the integrator positive when most of its swing has been used up by the positive common-mode voltage. For these critical applications, the integrator swing can be reduced to less than the recommended 4V full-scale swing, with some loss of accuracy. The integrator output can swing within 0.3V of either supply without loss of linearity.

### Analog Common

ANALOG COMMON (pin 3) is used as the - INPUT return during the auto-zero and deintegrate phases. If -INPUT is different from analog common, a common-mode voltage exists in the system. This signal is rejected by the excellent CMRR of the converter. In most applications, -INPUT will be set at a fixed known voltage (power supply common, for instance). In this application, analog common should be tied to the same point, thus removing the common-mode voltage from the converter. The reference voltage is referenced to analog common.

### Reference Voltage

The reference voltage input (REF IN, pin 2) must be a positive voltage with respect to analog common. Two reference voltage circuits are shown in Figure 5.

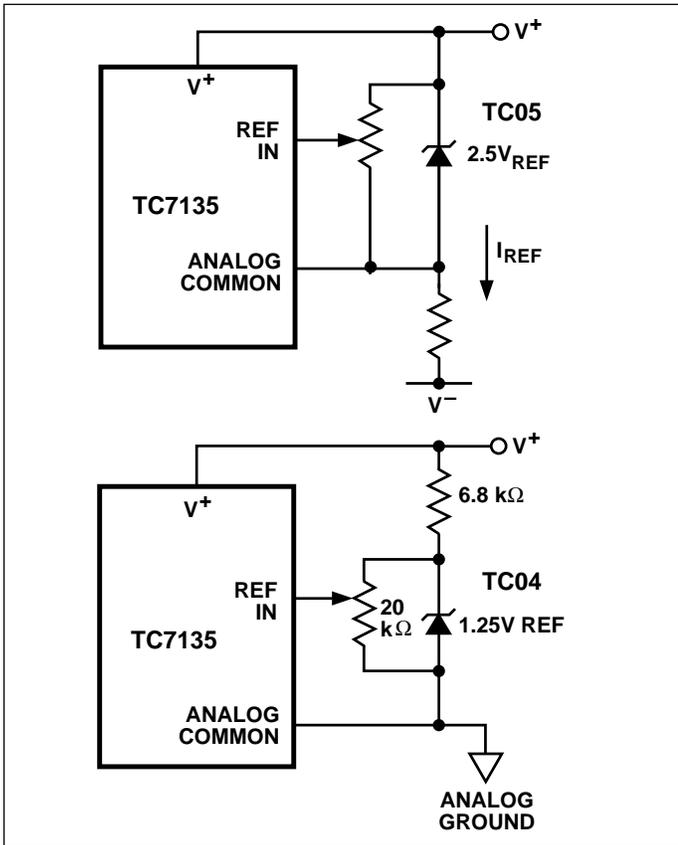


Figure 5. Using an External Reference Voltage

**Digital Section Functional Description**

The major digital subsystems within the TC7135 are illustrated in Figure 6, with timing relationships shown in Figure 7. The multiplexed BCD output data can be displayed on an LCD or LED display with the TC7211A (LCD) 4-digit display driver.

The digital section is best described through a discussion of the control signals and data outputs.

**RUN/HOLD Input**

When left open, the RUN/HOLD (R/H) input (pin 25) assumes a logic "1" level. With R/H = 1, the TC7135 performs conversions continuously, with a new measurement cycle beginning every 40,002 clock pulses.

When R/H changes to logic "0," the measurement cycle in progress will be completed, and data held and displayed, as long as the logic "0" condition exists.

A positive pulse (>300nsec) at R/H initiates a new measurement cycle. The measurement cycle in progress when R/H initially assumed logic "0" must be completed before the positive pulse can be recognized as a single conversion run command.

The new measurement cycle begins with a 10,001-count auto-zero phase. At the end of this phase, the busy signal goes high.

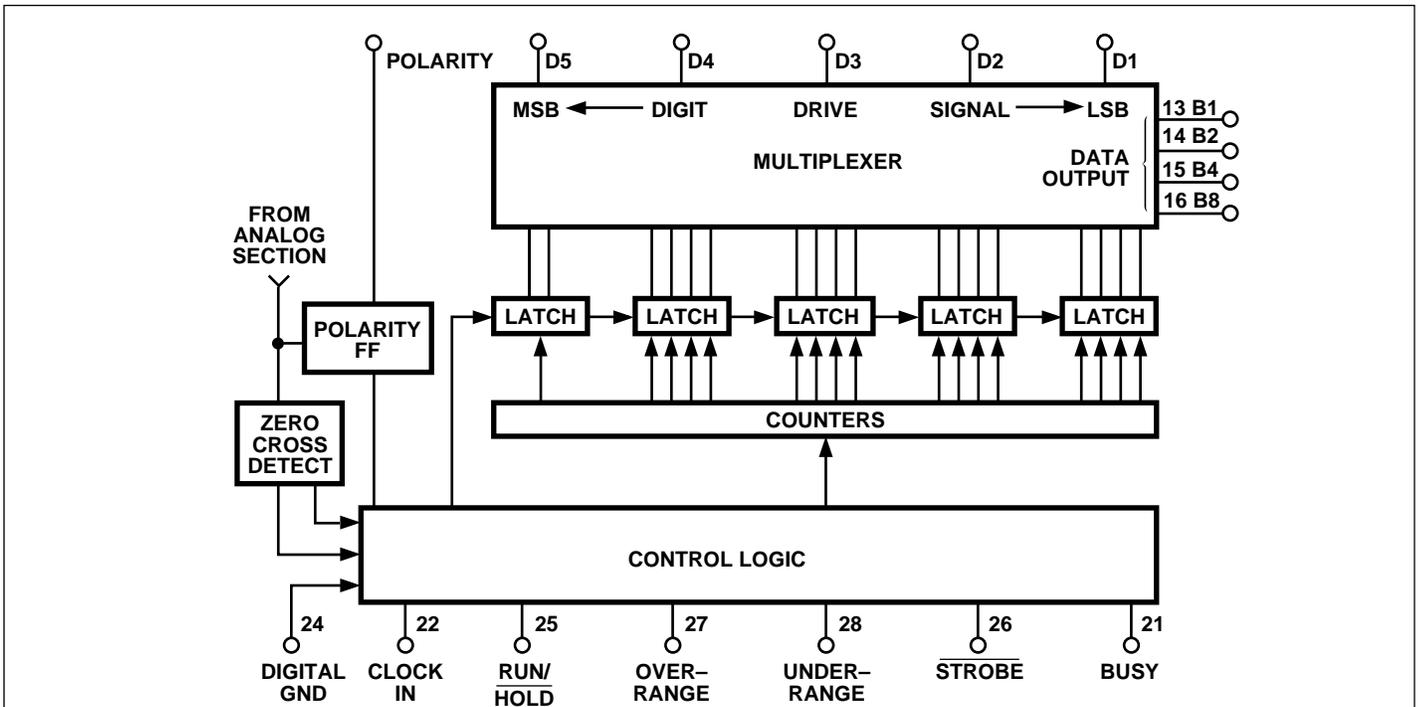


Figure 6. Digital Section Functional Diagram

## TC7135

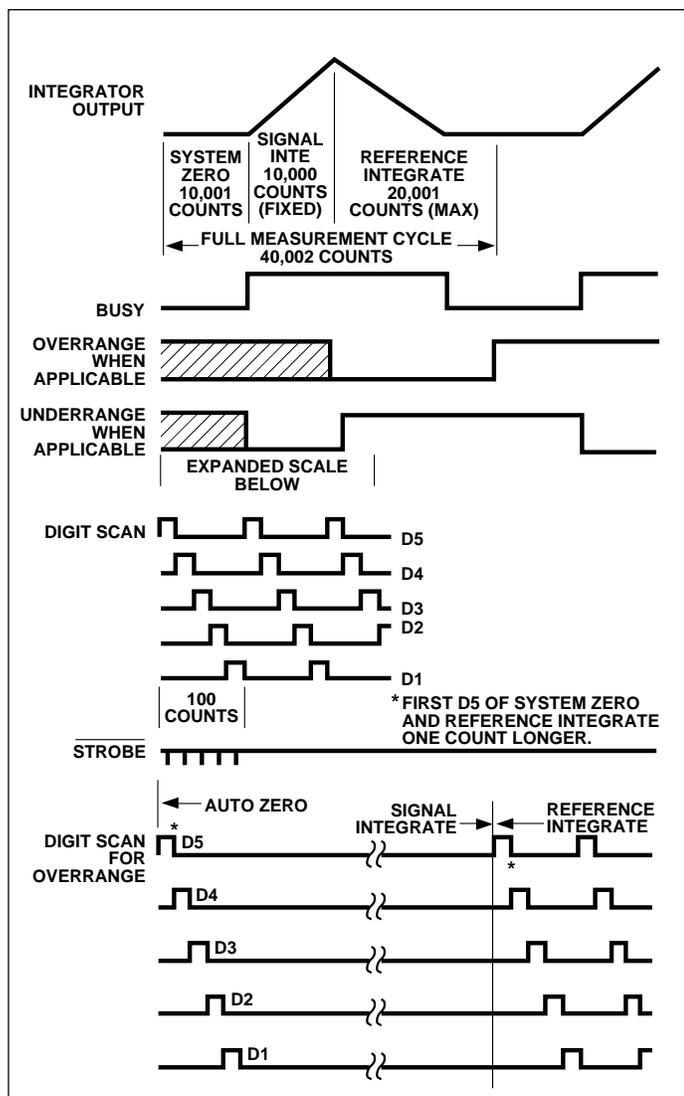


Figure 7. Timing Diagrams for Outputs

### STROBE Output

During the measurement cycle, the  $\overline{\text{STROBE}}$  output (pin 26) control line is pulsed low five times. The five low pulses occur in the center of the digit drive signals (D<sub>1</sub>, D<sub>2</sub>, D<sub>3</sub>, D<sub>4</sub> and D<sub>5</sub>; see Figure 8).

D<sub>5</sub> goes high for 201 counts when the measurement cycles end. In the center of D<sub>5</sub> pulse, 101 clock pulses after the end of the measurement cycle, the first  $\overline{\text{STROBE}}$  occurs for one-half clock pulse. After D<sub>5</sub> strobe, D<sub>4</sub> goes high for 200 clock pulses.  $\overline{\text{STROBE}}$  goes low 100 clock pulses after D<sub>4</sub> goes high. This continues through the D<sub>1</sub> drive pulse.

The digit drive signals will continue to permit display scanning.  $\overline{\text{STROBE}}$  pulses are not repeated until a new measurement is completed. The digit drive signals will not continue if the previous signal resulted in an overrange condition.

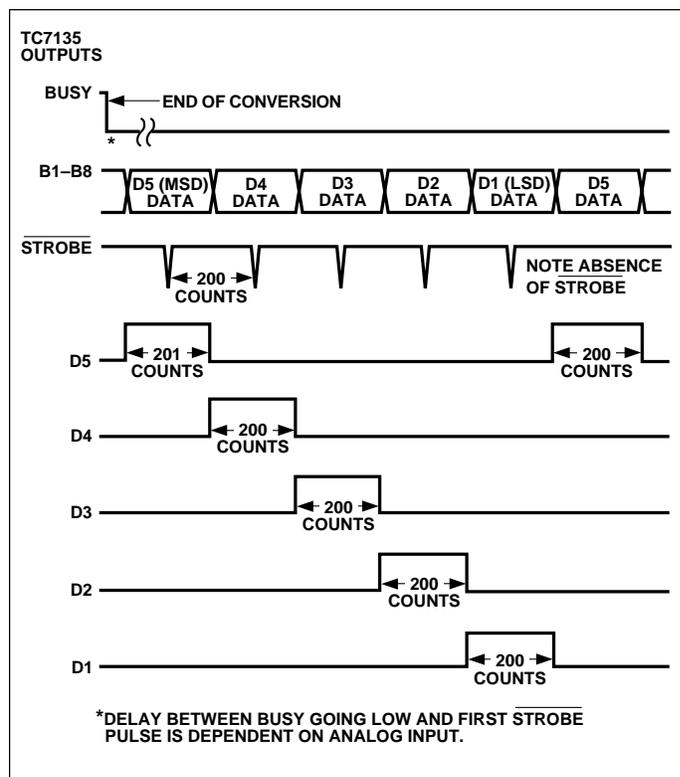


Figure 8. Strobe Signal Pulses Low Five Times per Conversion

The active-low  $\overline{\text{STROBE}}$  pulses aid BCD data transfer to UARTs, microprocessors, and external latches. (See Application Note AN-16.)

### BUSY Output

At the beginning of the signal-integration phase, BUSY (pin 21) goes high and remains high until the first clock pulse after the integrator zero crossing. BUSY returns to logic "0" after the measurement cycle ends in an overrange condition. The internal display latches are loaded during the first clock pulse after BUSY and are latched at the clock pulse end. The BUSY signal does not go high at the beginning of the measurement cycle, which starts with the auto-zero phase.

### OVERRANGE Output

If the input signal causes the reference voltage integration time to exceed 20,000 clock pulses, the OVERRANGE output (pin 27) is set to logic "1." The OVERRANGE output register is set when BUSY goes low and reset at the beginning of the next reference-integration phase.

### UNDERRANGE Output

If the output count is 9% of full scale or less ( $\leq 1800$  counts), the UNDERRANGE output (pin 28) register bit is set at the end of BUSY. The bit is set low at the next signal-integration phase.

### POLARITY Output

A positive input is registered by a logic "1" polarity signal. The POLARITY output (pin 23) is valid at the beginning of reference integrate and remains valid until determined during the next conversion.

The POLARITY bit is valid even for a zero reading. Signals less than the converter's LSB will have the signal polarity determined correctly. This is useful in null applications.

### Digit Drive Outputs

Digit drive outputs are positive-going signals. Their scan sequence is D<sub>5</sub>, D<sub>4</sub>, D<sub>3</sub>, D<sub>2</sub> and D<sub>1</sub> (pins 12, 17, 18, 19 and 20, respectively). All positive signals are 200 clock pulses wide, except D<sub>5</sub>, which is 201 clock pulses.

All five digits are continuously scanned, unless an overrange condition occurs. In an overrange condition, all digit drives are held low from the final  $\overline{\text{STROBE}}$  pulse until the beginning of the next reference-integrate phase. The scanning sequence is then repeated, providing a blinking visual display.

### BCD Data Outputs

The binary coded decimal (BCD) outputs, B<sub>8</sub>, B<sub>4</sub>, B<sub>2</sub> and B<sub>1</sub> (pins 16, 15, 14 and 13, respectively) are positive true-logic signals. They become active simultaneously with digit drive signals. In an overrange condition, all data bits are logic "0".

## APPLICATIONS INFORMATION

### Component Value Selection

#### Integrating Resistor

The integrating resistor (R<sub>INT</sub>) is determined by the full-scale input voltage and output current of the buffer used to charge the integrator capacitor (C<sub>INT</sub>). Both the buffer amplifier and the integrator have a Class A output stage, with 100μA of quiescent current. A 20μA drive current gives negligible linearity errors. Values of 5μA to 40μA give good results. The exact value of R<sub>INT</sub> for a 20μA current is easily calculated:

$$R_{INT} = \frac{\text{Full-scale voltage}}{20\mu\text{A}}$$

#### Integrating Capacitor

The product of R<sub>INT</sub> and C<sub>INT</sub> should be selected to give the maximum voltage swing to ensure tolerance buildup will not saturate integrator swing (approximately 0.3V from either supply). For ±5V supplies, and analog common tied to supply ground, a ±3.5V to ±4V full-scale integrator swing is

adequate. A 0.10μF to 0.47μF is recommended. In general, the value of C<sub>INT</sub> is given by:

$$C_{INT} = \frac{[10,000 \times \text{clock period}] \times I_{INT}}{\text{Integrator output voltage swing}}$$

$$= \frac{(10,000) (\text{clock period}) (20\mu\text{A})}{\text{Integrator output voltage swing}}$$

A very important characteristic of the C<sub>INT</sub> is that it has low dielectric absorption to prevent roll-over or ratiometric errors. A good test for dielectric absorption is to use the capacitor with the input tied to the reference. This ratiometric condition should read half-scale 0.9999. Any deviation is probably due to dielectric absorption. Polypropylene capacitors give undetectable errors at reasonable cost. Polystyrene and polycarbonate capacitors may also be used in less critical applications.

#### Auto-Zero and Reference Capacitors

The size of the auto-zero capacitor (C<sub>AZ</sub>) has some influence on system noise. A large capacitor reduces noise. The reference capacitor (C<sub>REF</sub>) should be large enough such that stray capacitance from its nodes to ground is negligible.

The dielectric absorption of C<sub>REF</sub> and C<sub>AZ</sub> is only important at power-on, or when the circuit is recovering from an overload. Smaller or cheaper capacitors can be used if accurate readings are not required during the first few seconds of recovery.

#### Reference Voltage

The analog input required to generate a full-scale output is V<sub>IN</sub> = 2 V<sub>REF</sub>.

The stability of the reference voltage is a major factor in overall absolute accuracy of the converter. Therefore, it is recommended that high-quality references be used where high-accuracy, absolute measurements are being made. Suitable references are:

Part Type	Manufacturer
TC04	Microchip Technology
TC05	Microchip Technology

### Conversion Timing

#### Line Frequency Rejection

A signal-integration period at a multiple of the 60Hz line frequency will maximize 60Hz "line noise" rejection.

A 100kHz clock frequency will reject 50Hz, 60Hz and 400Hz noise, corresponding to 2.5 readings per second.

## TC7135

**Table 2. Line Frequency Rejection**

Oscillator Frequency (kHz)	Frequency Rejected (Hz)
300, 200, 150, 120, 100, 40, 33-1/3	60
250, 166-2/3, 125, 100	50
100	50, 60, 400

**Table 3. Conversion Rate vs. Clock Frequency**

Conversion Rate (Conv/Sec)	Clock Frequency (kHz)
2.5	100
3.0	120
5.0	200
7.5	300
10.0	400
20.0	800
30.0	1200

## Displays and Driver Circuits

Microchip Technology manufactures three display decoder/driver circuits to interface the TC7135 to LCDs or LED displays. Each driver has 28 outputs for driving four 7-segment digit displays.

Device	Package	Description
TC7211AIPL	40-Pin Epoxy	4-Digit LCD Driver/Encoder

Several sources exist for LCDs and LED displays.

Manufacturer	Address	Display Type
Hewlett Packard Components	640 Page Mill Road Palo Alto, CA 94304	LED
AND	720 Palomar Ave. Sunnyvale, CA 94086	LCD and LED
Epson America, Inc.	3415 Kanhi Kawa St. Torrance, CA 90505	LCD

## High-Speed Operation

The maximum conversion rate of most dual-slope ADCs is limited by frequency response of the comparator. The comparator in this circuit follows the integrator ramp with a 3 $\mu$ s delay, and at a clock frequency of 160kHz (6 $\mu$ s period), half of the first reference integrate clock period is lost in delay. This means the meter reading will change from 0 to 1 with a 50 $\mu$ V input, 1 to 2 with 150 $\mu$ V, 2 to 3 with 250 $\mu$ V, etc. This transition at midpoint is considered desirable by most users; however, if clock frequency is increased appreciably above 160kHz, the instrument will flash "1" on noise peaks even when the input is shorted.

For many dedicated applications, where the input signal is always of one polarity, comparator delay need not be a limitation. Since nonlinearity and noise do not increase substantially with frequency, clock rates up to ~1MHz may be used. For a fixed clock frequency, the extra count (or counts) caused by comparator delay will be constant and can be digitally subtracted.

The clock frequency may be extended above 160kHz without this error, however, by using a low value resistor in series with the integrating capacitor. The effect of the resistor is to introduce a small pedestal voltage onto the integrator output at the beginning of reference-integrate phase. By careful selection of the ratio between this resistor and the integrating resistor (a few tens of ohms in the recommended circuit), the comparator delay can be compensated for and maximum clock frequency extended by approximately a factor of 3. At higher frequencies, ringing and second-order breaks will cause significant nonlinearities during the first few counts of the instrument.

The minimum clock frequency is established by leakage on the auto-zero and reference capacitors. With most devices, measurement cycles as long as 10 seconds give no measurable leakage error.

The clock used should be free from significant phase or frequency jitter. Several suitable low-cost oscillators are shown in the applications section. The multiplexed output means if the display takes significant current from the logic supply, the clock should have good PSRR.

### Zero-Crossing Flip-Flop

The flip-flop interrogates data once every clock pulse after transients of the previous clock pulse and half-clock pulse have died down. False zero-crossings caused by clock pulses are not recognized. Of course, the flip-flop delays the true zero-crossing by up to one count in every instance, and if a correction were not made, the display would always be one count too high. Therefore, the counter is disabled for one clock pulse at the beginning of the reference integrate (deintegrate) phase. This one-count delay compensates for the delay of the zero-crossing flip-flop, and allows the correct number to be latched into the display. Similarly, a one-count delay at the beginning of auto-zero gives an overload display of 0000 instead of 0001. No delay occurs during signal integrate, so true ratiometric readings result.

### Generating a Negative Supply

A negative voltage can be generated from the positive supply by using a TC7660. (See Figure 9.)

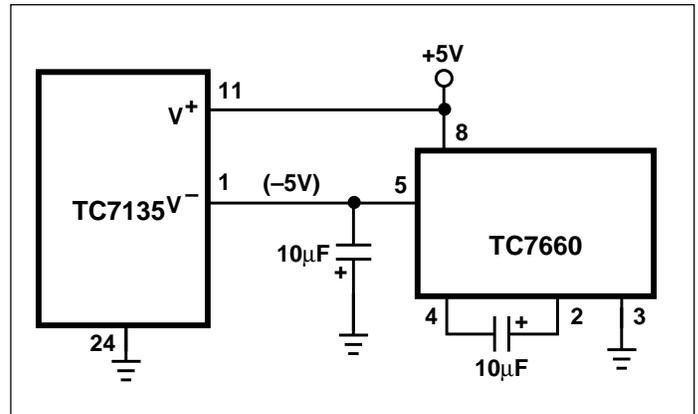
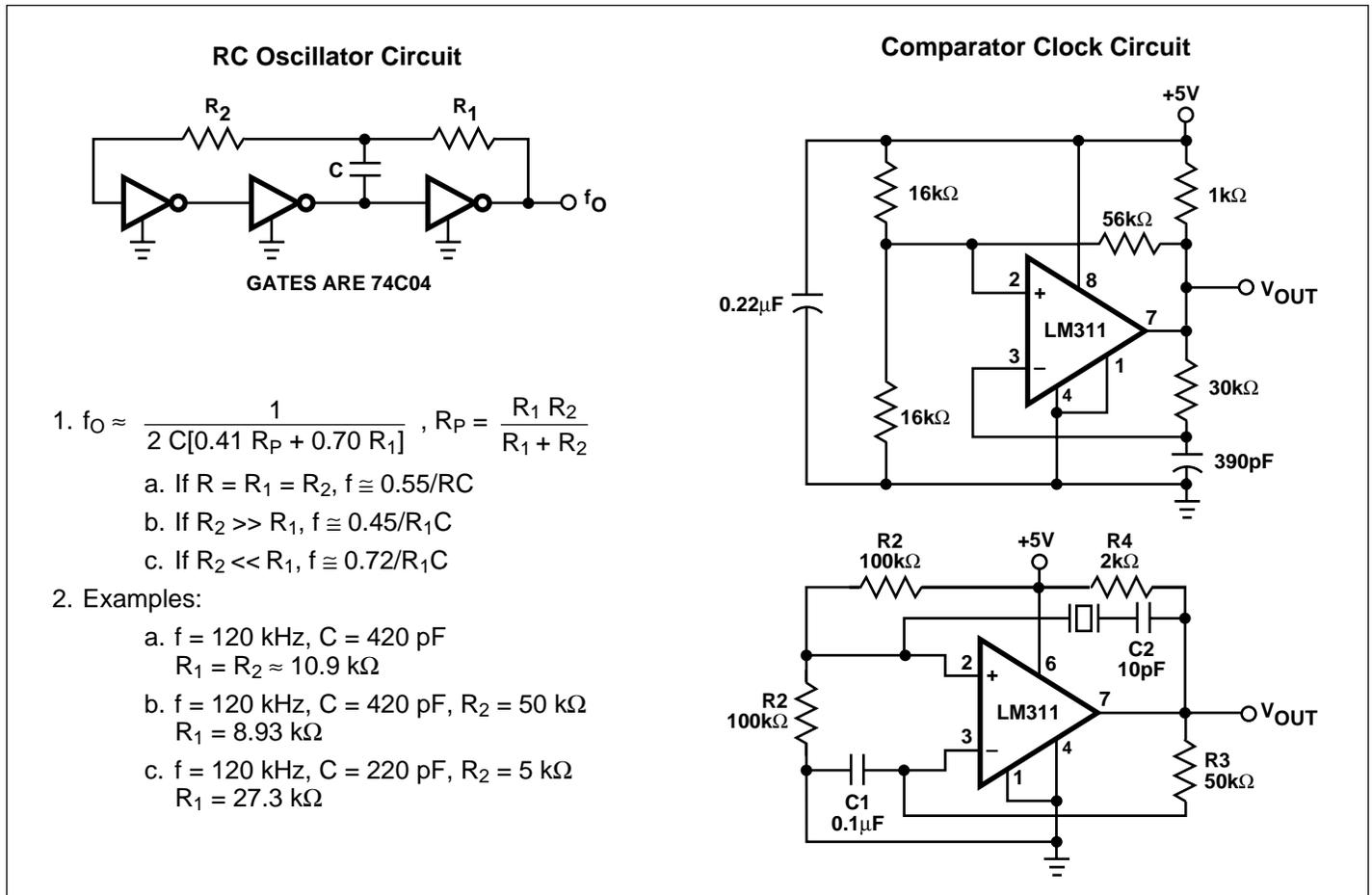


Figure 9. Negative Supply Voltage Generator

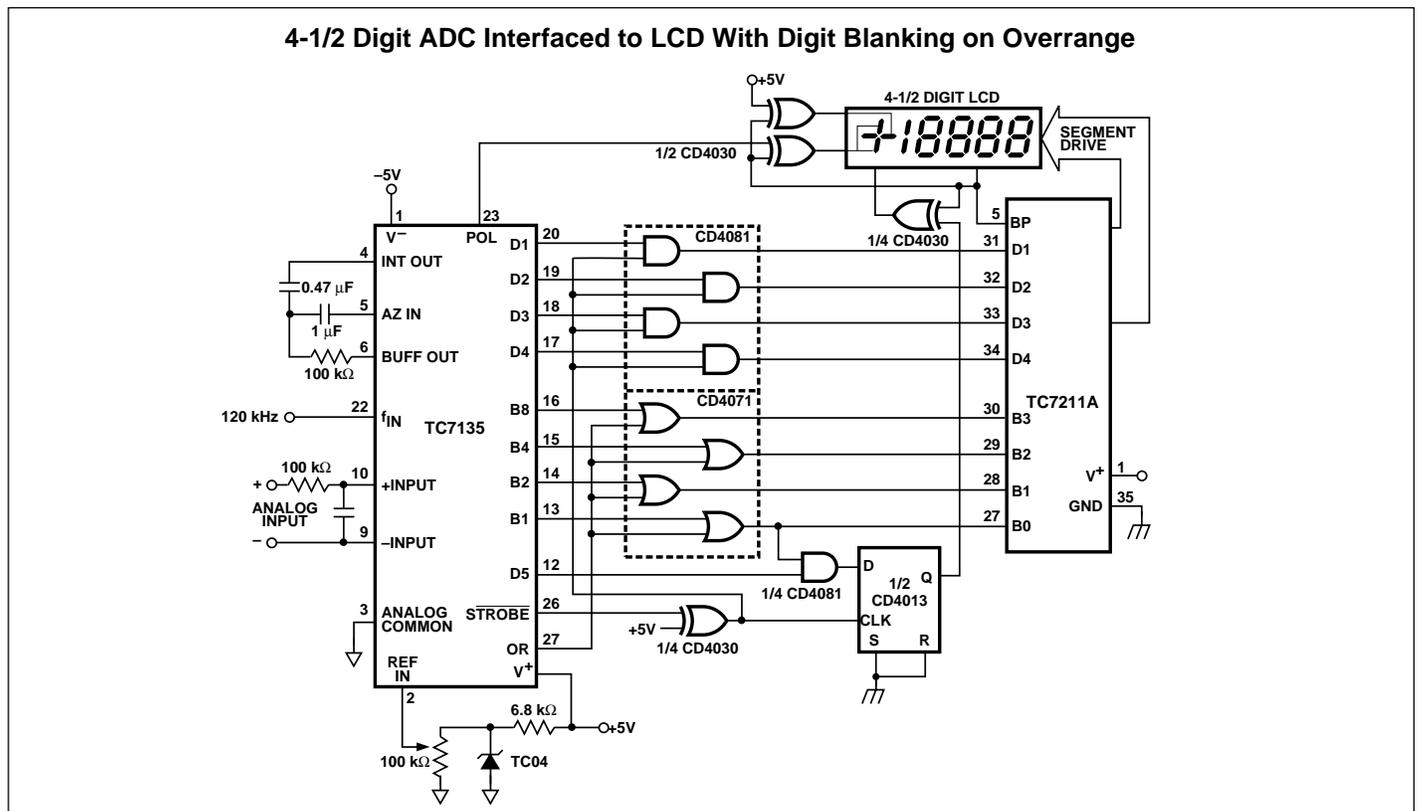
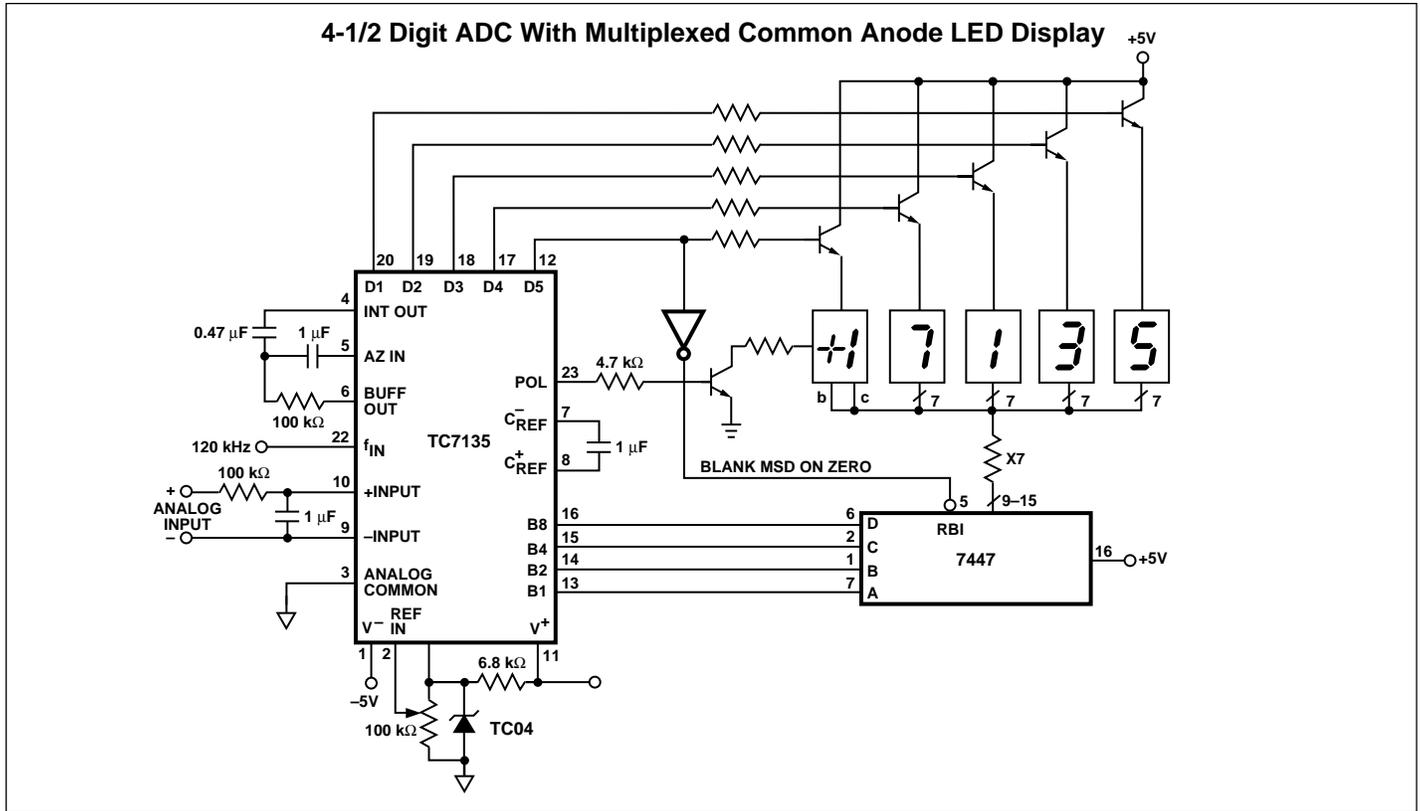
### TYPICAL APPLICATIONS



# 4-1/2 Digit Analog-To-Digital Converter

TC7135

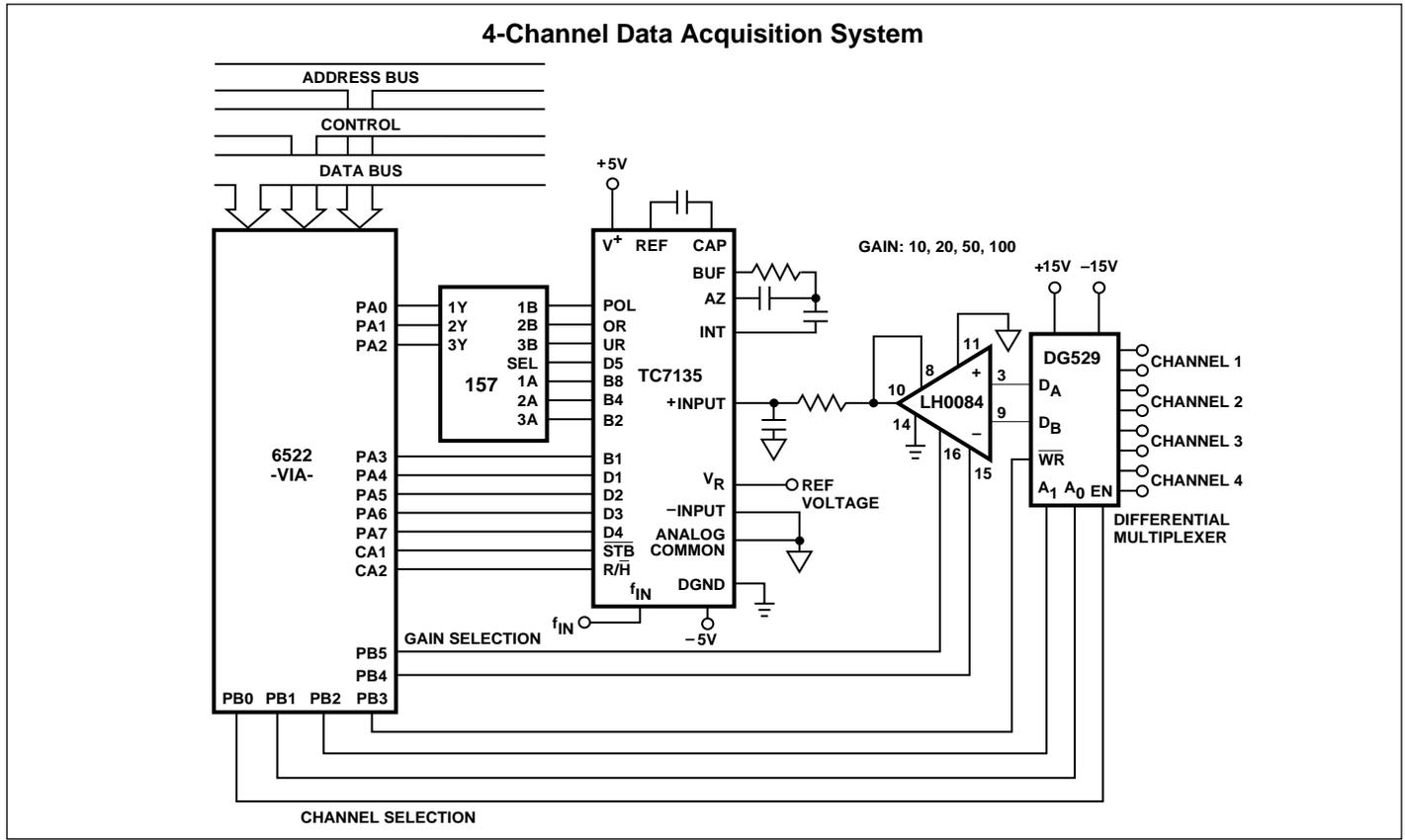
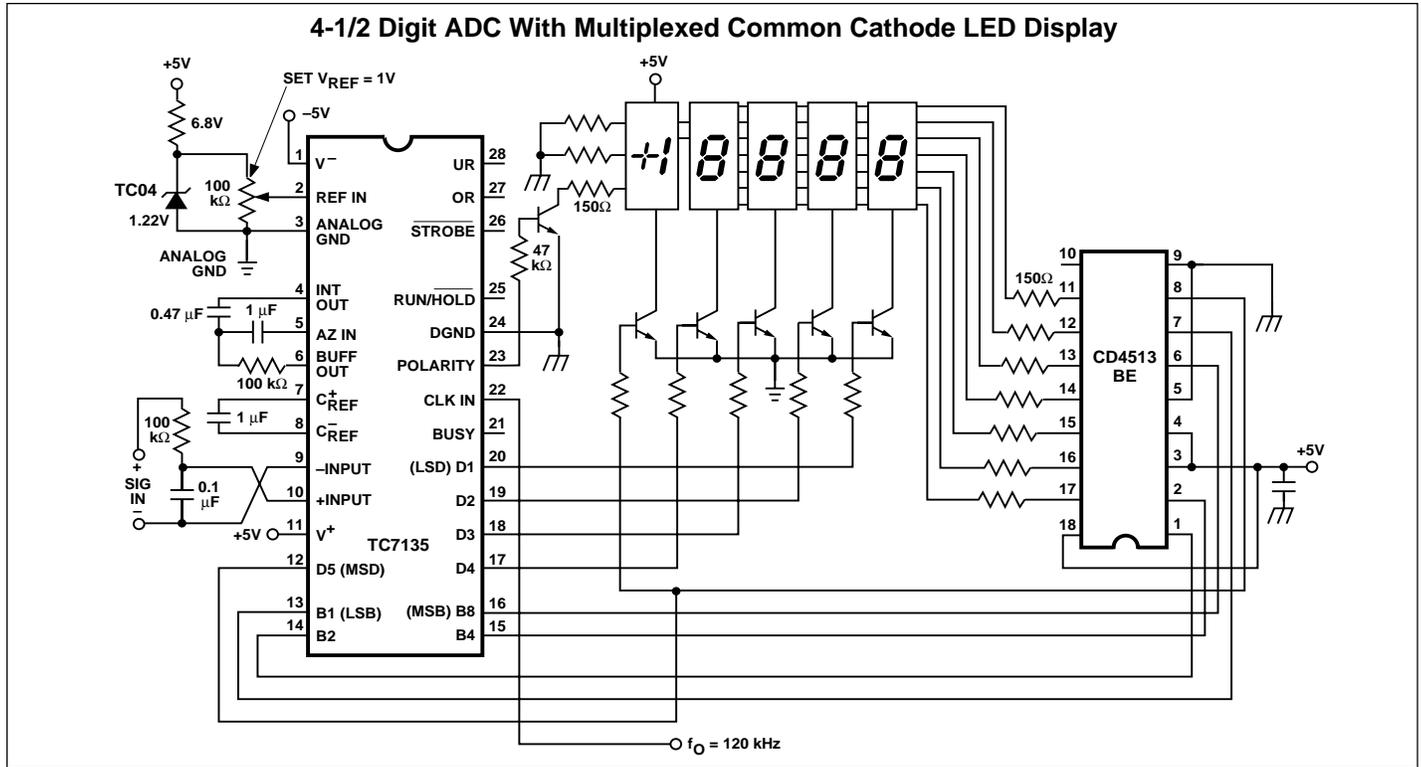
## TYPICAL APPLICATIONS (Cont.)



# 4-1/2 Digit Analog-To-Digital Converter

TC7135

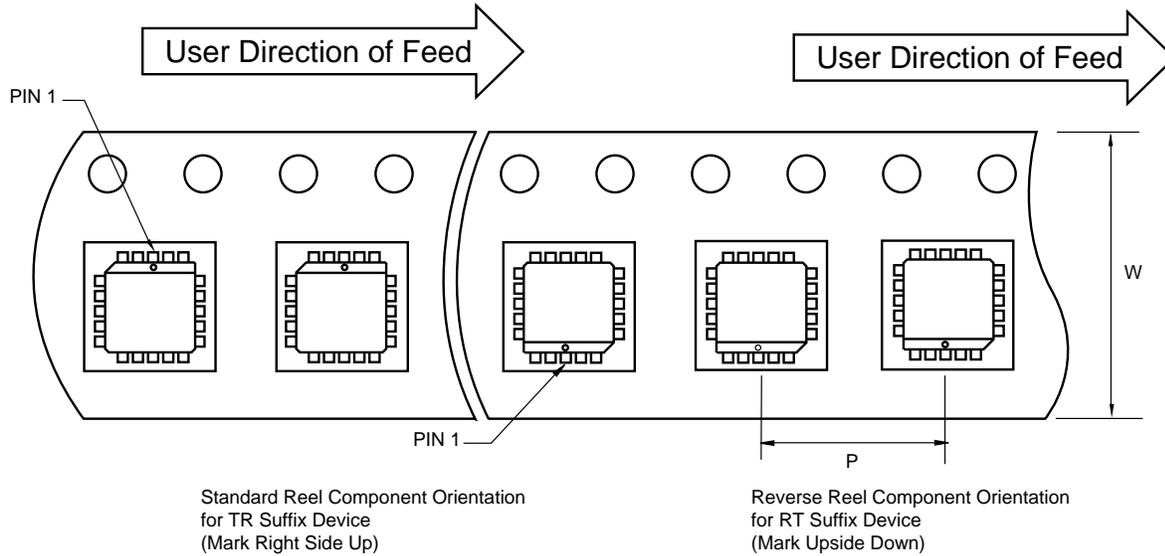
## TYPICAL APPLICATIONS (Cont.)



## TC7135

### TAPE AND REEL DIMENSIONS

Component Taping Orientation for 28-Pin PLCC Devices

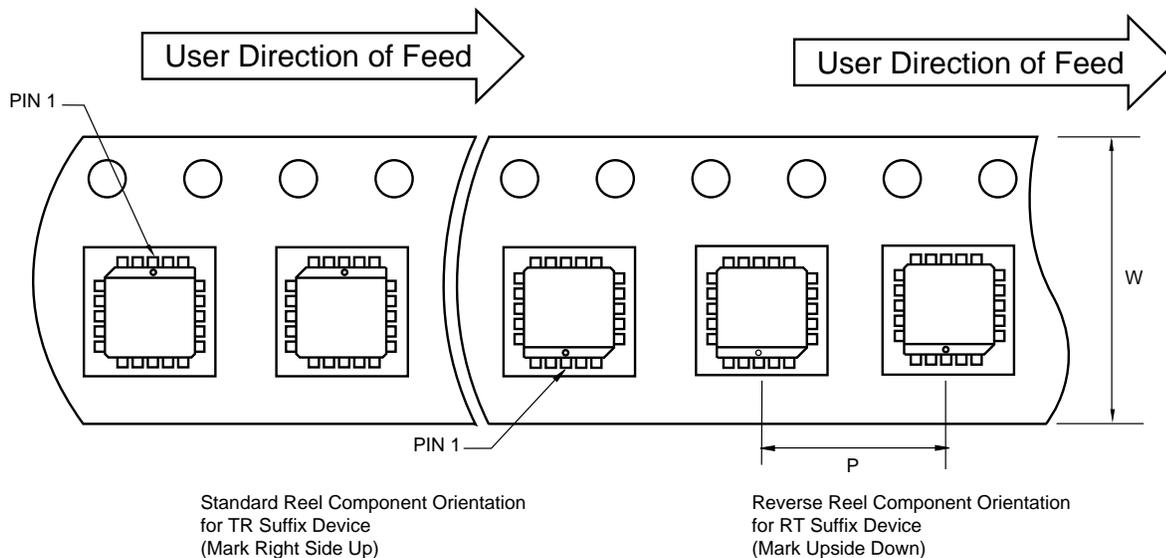


Carrier Tape, Number of Components Per Reel and Reel Size

Package	Carrier Width (W)	Pitch (P)	Part Per Full Reel	Reel Size
28-Pin PLCC	24 mm	16 mm	750	13 in

NOTE: Drawing does not represent total number of pins.

Component Taping Orientation for 28-Pin PLCC Devices



Carrier Tape, Number of Components Per Reel and Reel Size

Package	Carrier Width (W)	Pitch (P)	Part Per Full Reel	Reel Size
28-Pin PLCC	24 mm	16 mm	750	13 in

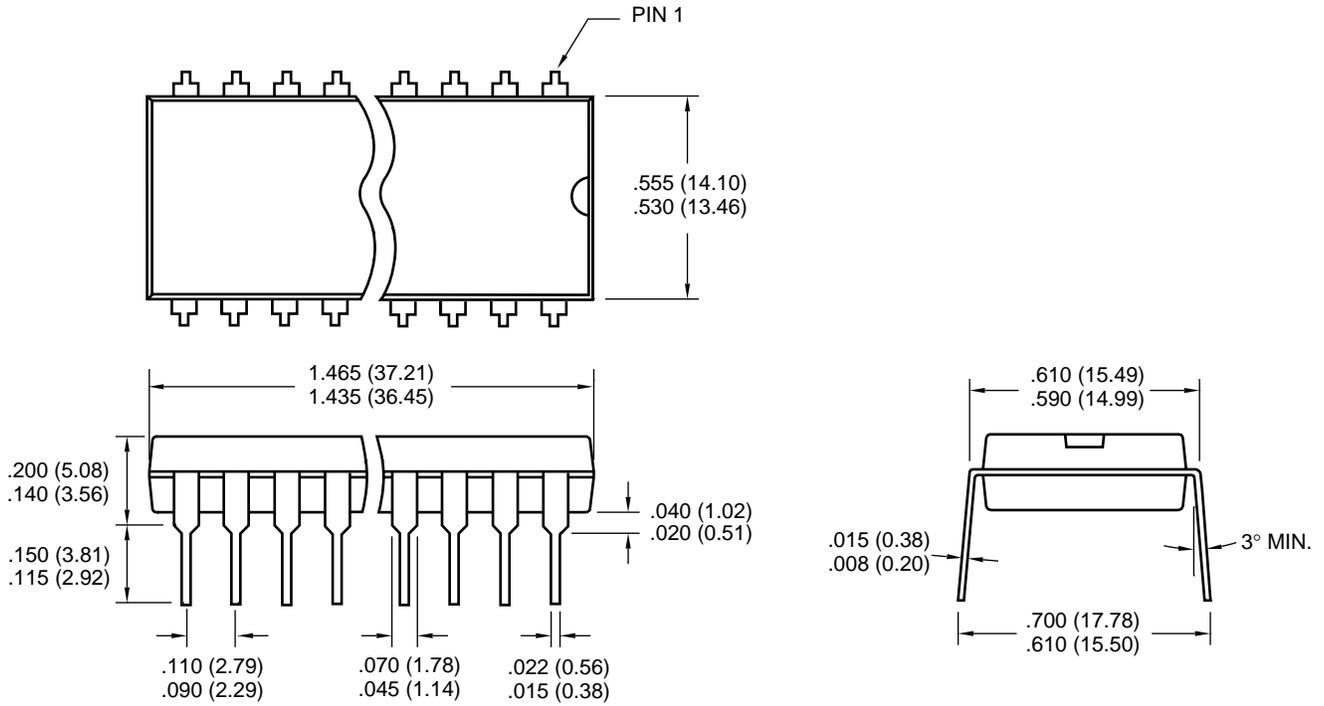
NOTE: Drawing does not represent total number of pins.

# 4-1/2 Digit Analog-To-Digital Converter

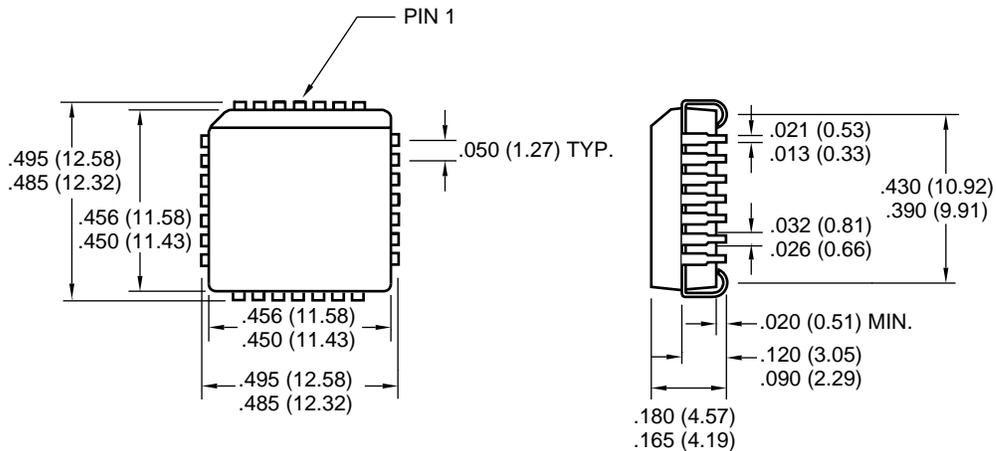
TC7135

## PACKAGE DIMENSIONS

28-Pin PDIP (Wide)



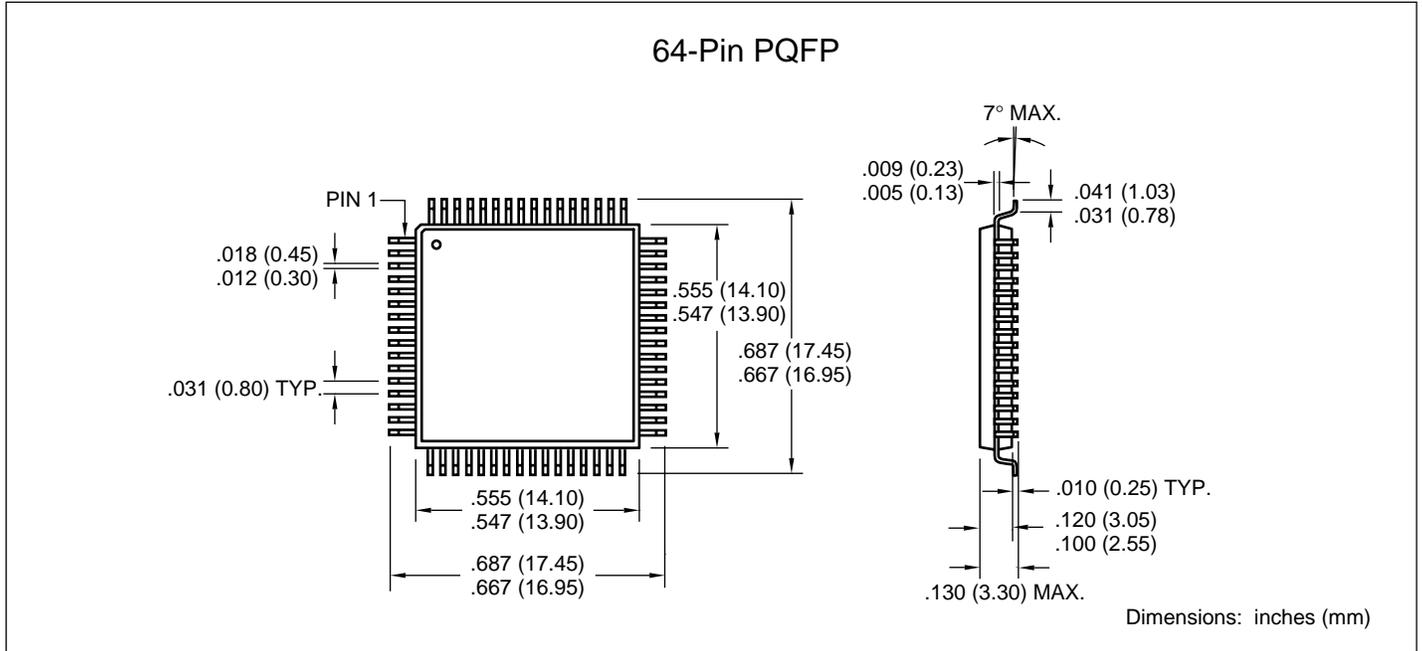
28-Pin PLCC



Dimensions: inches (mm)

## TC7135

### PACKAGE DIMENSIONS





## WORLDWIDE SALES AND SERVICE

### AMERICAS

#### Corporate Office

2355 West Chandler Blvd.  
Chandler, AZ 85224-6199  
Tel: 480-792-7200 Fax: 480-792-7277  
Technical Support: 480-792-7627  
Web Address: <http://www.microchip.com>

#### Rocky Mountain

2355 West Chandler Blvd.  
Chandler, AZ 85224-6199  
Tel: 480-792-7966 Fax: 480-792-7456

#### Atlanta

500 Sugar Mill Road, Suite 200B  
Atlanta, GA 30350  
Tel: 770-640-0034 Fax: 770-640-0307

#### Austin

Analog Product Sales  
8303 MoPac Expressway North  
Suite A-201  
Austin, TX 78759  
Tel: 512-345-2030 Fax: 512-345-6085

#### Boston

2 Lan Drive, Suite 120  
Westford, MA 01886  
Tel: 978-692-3848 Fax: 978-692-3821

#### Boston

Analog Product Sales  
Unit A-8-1 Millbrook Tarry Condominium  
97 Lowell Road  
Concord, MA 01742  
Tel: 978-371-6400 Fax: 978-371-0050

#### Chicago

333 Pierce Road, Suite 180  
Itasca, IL 60143  
Tel: 630-285-0071 Fax: 630-285-0075

#### Dallas

4570 Westgrove Drive, Suite 160  
Addison, TX 75001  
Tel: 972-818-7423 Fax: 972-818-2924

#### Dayton

Two Prestige Place, Suite 130  
Miamisburg, OH 45342  
Tel: 937-291-1654 Fax: 937-291-9175

#### Detroit

Tri-Atria Office Building  
32255 Northwestern Highway, Suite 190  
Farmington Hills, MI 48334  
Tel: 248-538-2250 Fax: 248-538-2260

#### Los Angeles

18201 Von Karman, Suite 1090  
Irvine, CA 92612  
Tel: 949-263-1888 Fax: 949-263-1338

#### Mountain View

Analog Product Sales  
1300 Terra Bella Avenue  
Mountain View, CA 94043-1836  
Tel: 650-968-9241 Fax: 650-967-1590

#### New York

150 Motor Parkway, Suite 202  
Hauppauge, NY 11788  
Tel: 631-273-5305 Fax: 631-273-5335

#### San Jose

Microchip Technology Inc.  
2107 North First Street, Suite 590  
San Jose, CA 95131  
Tel: 408-436-7950 Fax: 408-436-7955

#### Toronto

6285 Northam Drive, Suite 108  
Mississauga, Ontario L4V 1X5, Canada  
Tel: 905-673-0699 Fax: 905-673-6509

### ASIA/PACIFIC

#### China - Beijing

Microchip Technology Beijing Office  
Unit 915  
New China Hong Kong Manhattan Bldg.  
No. 6 Chaoyangmen Beidajie  
Beijing, 100027, No. China  
Tel: 86-10-85282100 Fax: 86-10-85282104

#### China - Shanghai

Microchip Technology Shanghai Office  
Room 701, Bldg. B  
Far East International Plaza  
No. 317 Xian Xia Road  
Shanghai, 200051  
Tel: 86-21-6275-5700 Fax: 86-21-6275-5060

#### Hong Kong

Microchip Asia Pacific  
RM 2101, Tower 2, Metroplaza  
223 Hing Fong Road  
Kwai Fong, N.T., Hong Kong  
Tel: 852-2401-1200 Fax: 852-2401-3431

#### India

Microchip Technology Inc.  
India Liaison Office  
Divyasree Chambers  
1 Floor, Wing A (A3/A4)  
No. 11, O'Shaughnessy Road  
Bangalore, 560 025, India  
Tel: 91-80-2290061 Fax: 91-80-2290062

#### Japan

Microchip Technology Intl. Inc.  
Benex S-1 6F  
3-18-20, Shinyokohama  
Kohoku-Ku, Yokohama-shi  
Kanagawa, 222-0033, Japan  
Tel: 81-45-471-6166 Fax: 81-45-471-6122

#### Korea

Microchip Technology Korea  
168-1, Youngbo Bldg. 3 Floor  
Samsung-Dong, Kangnam-Ku  
Seoul, Korea  
Tel: 82-2-554-7200 Fax: 82-2-558-5934

### ASIA/PACIFIC (continued)

#### Singapore

Microchip Technology Singapore Pte Ltd.  
200 Middle Road  
#07-02 Prime Centre  
Singapore, 188980  
Tel: 65-334-8870 Fax: 65-334-8850

#### Taiwan

Microchip Technology Taiwan  
11F-3, No. 207  
Tung Hua North Road  
Taipei, 105, Taiwan  
Tel: 886-2-2717-7175 Fax: 886-2-2545-0139

### EUROPE

#### Australia

Microchip Technology Australia Pty Ltd  
Suite 22, 41 Rawson Street  
Epping 2121, NSW  
Australia  
Tel: 61-2-9868-6733 Fax: 61-2-9868-6755

#### Denmark

Microchip Technology Denmark ApS  
Regus Business Centre  
Lautrup høj 1-3  
Ballerup DK-2750 Denmark  
Tel: 45 4420 9895 Fax: 45 4420 9910

#### France

Arizona Microchip Technology SARL  
Parc d'Activite du Moulin de Massy  
43 Rue du Saule Trapu  
Batiment A - ler Etage  
91300 Massy, France  
Tel: 33-1-69-53-63-20 Fax: 33-1-69-30-90-79

#### Germany

Arizona Microchip Technology GmbH  
Gustav-Heinemann Ring 125  
D-81739 Munich, Germany  
Tel: 49-89-627-144 0 Fax: 49-89-627-144-44

#### Germany

Analog Product Sales  
Lochhamer Strasse 13  
D-82152 Martinsried, Germany  
Tel: 49-89-895650-0 Fax: 49-89-895650-22

#### Italy

Arizona Microchip Technology SRL  
Centro Direzionale Colleoni  
Palazzo Taurus 1 V. Le Colleoni 1  
20041 Agrate Brianza  
Milan, Italy  
Tel: 39-039-65791-1 Fax: 39-039-6899883

#### United Kingdom

Arizona Microchip Technology Ltd.  
505 Eskdale Road  
Winnersh Triangle  
Wokingham  
Berkshire, England RG41 5TU  
Tel: 44 118 921 5869 Fax: 44-118 921-5820

All rights reserved. © 2001 Microchip Technology Incorporated. Printed in the USA. 1/01  Printed on recycled paper.

01/09/01

Information contained in this publication regarding device applications and the like is intended through suggestion only and may be superseded by updates. It is your responsibility to ensure that your application meets with your specifications. No representation or warranty is given and no liability is assumed by Microchip Technology Incorporated with respect to the accuracy or use of such information, or infringement of patents or other intellectual property rights arising from such use or otherwise. Use of Microchip's products as critical components in life support systems is not authorized except with express written approval by Microchip. No licenses are conveyed, implicitly or otherwise, except as maybe explicitly expressed herein, under any intellectual property rights. The Microchip logo and name are registered trademarks of Microchip Technology Inc. in the U.S.A. and other countries. All rights reserved. All other trademarks mentioned herein are the property of their respective companies.